Electronic Supplementary Material (ESI) for Physical Chemistry Chemical Physics.

Supplementary Material

Latent Track Formation and Recrystallization in Swift Heavy Ion Irradiation

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Table S1. Latent track radius in rutile TiO_2 for various ions.

SHI	**Se (keV/nm)**	**R (nm) - Experimental**[1]	**R (nm) – Numerical PF-i-TS**	**R (nm) – Numerical Classical i-TS**
23 MeV I	8.86	0	0	2
28 MeV I	10.94	0	0	4.5
84.5 MeV Cu	13.6	1.5±0.4	1.66	5
79 MeV Br	15.2	2.4±1.2	2.9	5.33
115 MeV Br	16.1	3.8±0.4	3.42	5.8

References:

[1] K. Awazu, X. Wang, M. Fujimaki, T. Komatsubara, T. Ikeda, Y. Ohki, J Appl Phys 100 (2006) 044308.